

Search Notes 	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/790,030	AOKI ET AL.	
	Examiner EDMUND H. LEE	Art Unit 1732	

SEARCHED

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
264	250,255	9/17/2007	EHL
	269		J